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R&D of EOTD bunch length monitor for SXFEL

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As one of on-line single-shot and non-destructive absolute measure methods with high resolution, Electro-Optical (EO) techniques have been widely utilized in Free Electron Laser to measure the longitudinal bunch profile. A bunch length monitor with 100 fs resolution is required for Shanghai Soft X-ray FEL (SXFEL) facility. The solution based on Electro-Optical Temporal Decoding (EOTD) method has been developed and tested during the past year. This paper will present the whole design according to SXFEL condition and its first test results.

Funding Agency

Footnotes

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Yes

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